

Amendments to the Claims:

Please cancel claims 1-35 and 37-50 without prejudice or disclaimer. This listing of claims will replace all prior versions and listings of claims in the application:

Listing of Claims:

1-35. (Cancelled)

36. (Original) An electronic equipment comprising:

a processor incorporating a delay circuit element whose delay time changes depending on a temperature;

a detection circuit, connected to said delay circuit element, for detecting an internal temperature of said processor from a change in response delay of said delay circuit element; and

clock control means for controlling a clock signal supplied to said processor such that an operating speed of said processor is decreased when the internal temperature detected by said detection circuit exceeds a first temperature.

37-50. (Cancelled)

51. (New) An electronic apparatus comprising:

a semiconductor circuit including an element having a characteristic that varies with temperature and outputting a signal corresponding to the characteristic of the element, the semiconductor circuit operating according to a clock frequency;

a temperature detecting element configured to detect a temperature of the semiconductor circuit based on the signal of the semiconductor circuit; and

a system power controller configured to control the clock frequency of the semiconductor circuit to be decreased when the temperature detected by the temperature detecting element exceeds a first threshold, and to control the electronic apparatus to be powered off when the temperature detected by the temperature detecting element exceeds a second threshold higher than the first threshold.

52. (New) The electronic apparatus according to claim 51, wherein the temperature detecting element includes a p-n junction circuit element.

53. (New) The electronic apparatus according to claim 51, wherein the semiconductor circuit includes a CPU.

54. (New) A control method applied to an electronic apparatus having a semiconductor circuit including an element having a characteristic that varies with temperature and outputting a signal corresponding to the characteristic of the element, the semiconductor circuit operating according to a clock frequency, the method comprising:

detecting a temperature of the semiconductor circuit based on the signal of the semiconductor circuit; and

controlling the clock frequency of the semiconductor circuit to be decreased by a system power controller when the temperature detected in the detection exceeds a first threshold, and controlling the electronic apparatus to be powered off by the system power controller when the temperature detected in the detection exceeds a second threshold higher than the first threshold.

55. (New) An electronic apparatus comprising:

a circuit;

a temperature detection unit configured to detect a temperature of the circuit to output a logical signal outside of the temperature detection unit when the detected temperature exceeds a threshold; and

a system power controller configured to power off the electronic apparatus based on the logical signal output from the temperature detection unit.

56. (New) The electronic apparatus according to claim 55, wherein the circuit includes a CPU.

57. (New) A computer comprising:

a circuit;

a temperature detection portion configured to detect a temperature of the circuit and to output an analog signal based on the temperature to outside of the temperature detection portion;

an analog-digital converter configured to convert the analog signal from the temperature detection portion to a digital signal; and

a system power controller configured to control the computer to be powered off when a value of the digital signal exceeds a threshold value.

58. (New) The computer according to claim 57, wherein the temperature detection portion includes a p-n junction circuit element.

59. (New) The computer according to claim 57, wherein the circuit includes a CPU.